

Issue Classification	Applicant(s)/Patent Under Reexamination		
Application/Control No.	10775356	WANG, JIAN	Art Unit
Examiner	Chapel, Derek S		2872
			

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<i>Derek S. Chapel</i> (Legal Instruments Examiner)	<i>6/12/07</i> (Date)	<i>Arnel Lavarias</i> ARNEL LAVARIAS PRIMARY PATENT EXAMINER (Primary Examiner)	O.G. Print Claim(s) 42 O.G. Print Figure 4

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